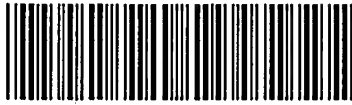


Search Notes

Application/Control No.

10/760,177

Examiner

Mark H. Paschall

Applicant(s)/Patent under
Reexamination

CONWAY ET AL.

Art Unit

3742

SEARCHED

Class	Subclass	Date	Examiner
219	121.49		
	121.52		
	2544	7/23/05	n
	121.48		
	121.5		
	121.51		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East enclosed.	7/23/05	n